ANALOG DEVICES

Nonvolatile, I²C-Compatible 64-Position, Digital Potentiometer

FUNCTIONAL BLOCK DIAGRAMS

AD5258

FEATURES

Nonvolatile memory maintains wiper settings 64-position Compact MSOP-10 (3 mm × 4.9 mm) package I²C°-compatible interface V_{LOGIC} pin provides increased interface flexibility End-to-end resistance 1 k Ω , 10 k Ω , 50 k Ω , 100 k Ω Resistance tolerance stored in EEPROM (0.1% accuracy) Power-on EEPROM refresh time <1 ms Software write protect command Three-state Address Decode Pins AD0 and AD1 allow 9 packages per bus 100-year typical data retention at 55°C Wide operating temperature –40°C to +85°C 3 V to 5 V single supply

APPLICATIONS

LCD panel V_{COM} adjustment LCD panel brightness and contrast control Mechanical potentiometer replacement in new designs Programmable power supplies RF amplifier biasing Automotive electronics adjustment Gain control and offset adjustment Fiber to the home systems Electronics level settings

GENERAL DESCRIPTION

The AD5258 provides a compact, nonvolatile 3 mm \times 4.9 mm packaged solution for 64-position adjustment applications. These devices perform the same electronic adjustment function as mechanical potentiometers¹ or variable resistors, but with enhanced resolution and solid-state reliability.

The wiper settings are controllable through an I²C-compatible digital interface that is also used to read back the wiper register and EEPROM content. Resistor tolerance is also stored within EEPROM providing an end-to-end tolerance accuracy of 0.1%. There is also a software write protection function that ensures data cannot be written to the EEPROM register.

A separate $V_{\rm LOGIC}\,pin$ delivers increased interface flexibility. For users who need multiple parts on one bus, Address Bit AD0 and Address Bit AD1 allow up to nine devices on the same bus.

Rev. 0

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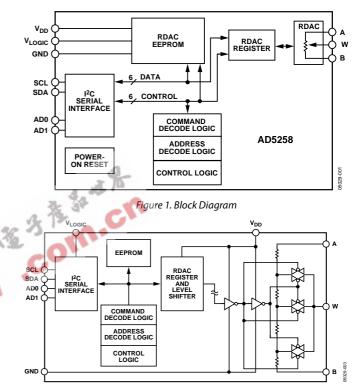


Figure 2. Block Diagram Showing Level Shifters

CONNECTION DIAGRAM

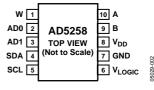


Figure 3. Pinout

¹ The terms digital potentiometer, VR (variable resistor), and RDAC are used interchangeably.

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SPECIFICATIONS

ELECTRICAL CHARACTERISTICS

 $V_{\text{DD}} = V_{\text{LOGIC}} = 5 \text{ V} \pm 10\%, \text{ or } 3 \text{ V} \pm 10\%; V_{\text{A}} = V_{\text{DD}}; V_{\text{B}} = 0 \text{ V}; -40^{\circ}\text{C} < T_{\text{A}} < +85^{\circ}\text{C}, \text{ unless otherwise noted.}$

Table 1. Parameter	Symbol	Conditions	Min	Typ ¹	Max	Unit
DC CHARACTERISTICS: RHEOSTAT MODE				-76		
Resistor Differential Nonlinearity	R-DNL	R_{WB} , V_A = no connect				LSB
1 kΩ			-1.5	±0.3	+1.5	
10 kΩ/50 kΩ/100 kΩ			-0.25	±0.1	+0.25	
Resistor Integral Nonlinearity	R-INL	R _{WB} , V _A = no connect	0.20			LSB
1 kΩ			-5	±0.5	+5	200
10 kΩ/100 kΩ			-0.5	±0.1	+0.5	
50 kΩ			-0.25	±0.1	+0.25	
Nominal Resistor Tolerance		$T_A = 25^{\circ}C, V_{DD} = 5.5 V$				
1 kΩ	Rab		0.9		1.5	kΩ
10 kΩ/50 kΩ/100 kΩ	ΔR_{AB}	0	-30		+30	%
Resistance Temperature Coefficient	$(\Delta R_{AB} \times 10^6)/(R_{AB} \times \Delta T)$	Code = 0x00/0x20	50	200/15	150	ppm/°C
Total Wiper Resistance	RwB			75	350	ρρ, c Ω
DC CHARACTERISTICS:		Code = 0x00		, ,	550	
POTENTIOMETER DIVIDER MODE		10 3				
Differential Nonlinearity	DNL	132				LSB
1 kΩ		CO.	-1	±0.3	+1	
10 kΩ/50 kΩ/100 kΩ			-0.25	±0.1	+0.25	
Integral Nonlinearity	INL					LSB
1 kΩ			-1	±0.3	+1	
10 kΩ/50 kΩ/100 kΩ			-0.25	±0.1	+0.25	
Full-Scale Error	Vwfse	Code = 0x3F				LSB
1 kΩ			-6	-3	0	
10 kΩ			-1	-0.3	0	
50 kΩ/100 kΩ			-1	-0.1	0	
Zero-Scale Error	V _{WZSE}	Code = 0x00				LSB
1 kΩ			0	3	5	
10 kΩ			0	0.3	1	
50 kΩ/100 kΩ			0	0.1	0.5	
Voltage Divider Temperature	$(\Delta V_W \times 10^6)/(V_W \times \Delta T)$	Code = 0x00/0x20		120/15		ppm/°C
Coefficient						
RESISTOR TERMINALS						
Voltage Range	V _{A, B, W}		GND		V_{DD}	V
Capacitance A, B	Са, в	f = 1 MHz, measured to GND, code = 0x20		45		рF
Capacitance W	Cw	f = 1 MHz, measured to GND, code = 0x20		60		pF
Common-Mode Leakage	Ісм	$V_A = V_B = V_{DD}/2$		10		nA
DIGITAL INPUTS AND OUTPUTS						
Input Logic High	VIH		$0.7 \times V_L$		$V_{L} + 0.5$	V
Input Logic Low	VIL		-0.5		$0.3 \times V_{L}$	v
Leakage Current	IL					μA
SDA, AD0, AD1		$V_{IN} = 0 V \text{ or } 5 V$		0.01	±1	
SCL – Logic High		$V_{IN} = 0 V$	-2.5	-1.4	+1	
SCL – Logic Low		$V_{IN} = 5 V$		0.01	±1	
Input Capacitance	C _{IL}			5		pF

Parameter	Symbol	Conditions	Min	Typ ¹	Max	Unit
POWER SUPPLIES						
Power Supply Range	V _{DD}		2.7		5.5	v
Positive Supply Current	IDD			0.5	2	μΑ
Logic Supply	VLOGIC		2.7		5.5	V
Logic Supply Current	ILOGIC	$V_{IH} = 5 V \text{ or } V_{IL} = 0 V$		3.5	6	μΑ
Programming Mode Current (EEPROM)	LOGIC(PROG)	$V_{IH} = 5 V \text{ or } V_{IL} = 0 V$		35		mA
Power Dissipation	P _{DISS}	$V_{IH} = 5 V \text{ or } V_{IL} = 0 V, V_{DD} = 5 V$		20	40	μW
Power Supply Rejection Ratio	PSRR	$V_{DD} = +5 V \pm 10\%$, Code = 0x20		±0.01	±0.06	%/%
DYNAMIC CHARACTERISTICS						
Bandwidth –3 dB	BW	Code = 0x20				
		$R_{AB} = 1 \ k\Omega$		18000		kHz
		$R_{AB} = 10 \ k\Omega$		1000		kHz
		$R_{AB} = 50 \ k\Omega$		190		kHz
		$R_{AB} = 100 \text{ k}\Omega$		100		kHz
Total Harmonic Distortion	THDw	$\label{eq:RAB} \begin{split} R_{AB} &= 10 \; k\Omega, V_A = 1 \; V \; rms, V_B = 0, \\ f &= 1 \; kHz \end{split}$		0.1		%
V _w Settling Time	ts	$R_{AB} = 10 \text{ k}\Omega, V_{AB} = 5 \text{ V},$ ±1 LSB error band		500		ns
Resistor Noise Voltage Density	e _{N_WB}	$R_{WB} = 5 k\Omega, f = 1 kHz$	•	9		nV/√⊦
¹ Typical values represent average readings at 25	$^{\circ}$ C and $V_{DD} = 5$ V.	$R_{WB} = 5 k\Omega, f = 1 kHz$				

TIMING CHARACTERISTICS

 $V_{DD} = V_{LOGIC} = 5 V \pm 10\%$, or $3 V \pm 10\%$; $V_A = V_{DD}$; $V_B = 0 V$; $-40^{\circ}C < T_A < +85^{\circ}C$, unless otherwise noted.

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
I ² C INTERFACE TIMING CHARACTERISTICS						
SCL Clock Frequency	fscl		0		400	kHz
t_{BUF} Bus Free Time between STOP and START	t ₁		1.3			μs
t _{HD,STA} Hold Time (Repeated START)	t ₂	After this period, the first clock pulse is generated.	0.6			μs
t _{LOW} Low Period of SCL Clock	t ₃		1.3			μs
t _{HIGH} High Period of SCL Clock	t4		0.6			μs
t _{su;sta} Setup Time for Repeated START Condition	t ₅		0.6			μs
t _{HD;DAT} Data Hold Time	t ₆		0		0.9	μs
tsu;dat Data Setup Time	t7		100			ns
t _F Fall Time of Both SDA and SCL Signals	t ₈				300	ns
t_R Rise Time of Both SDA and SCL Signals	t9	.a			300	ns
tsu;sto Setup Time for STOP Condition	t10	I D	0.6			μs
EEPROM Data Storing Time	teemem_store	7. 53		26		ms
EEPROM Data Restoring Time at Power On ¹	t EEMEM_RESTORE1	V_{DD} rise time dependant. Measure without decoupling capacitors at V_{DD} and GND.		300		μs
EEPROM Data Restoring Time upon Restore Command ¹	teemem_restore2	$V_{DD} = 5 V.$		300		μs
EEPROM Data Rewritable Time ²				540		μs
FLASH/EE MEMORY RELIABILITY						
Endurance ³			100	700		kCyc
Data Retention ⁴				100		Years

¹ During power-up, the output is momentarily preset to midscale before restoring EEPROM content. ² Delay time after power-on PRESET prior to writing new EEPROM data. ³ Endurance is qualified to 100,000 cycles per JEDEC Std. 22 method A117, and is measured at -40°C, +25°C, and +85°C; typical endurance at +25°C is 700,000 cycles. ⁴ Retention lifetime equivalent at junction temperature (T_i) = 55°C per JEDEC Std. 22, Method A117. Retention lifetime based on an activation energy of 0.6eV derates with junction temperature.

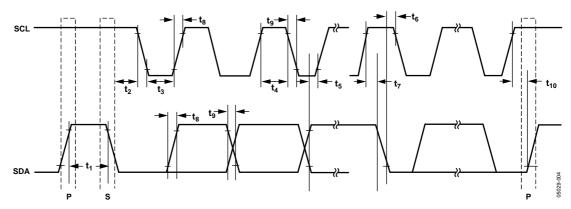


Figure 4. I²C Interface Timing Diagram

ABSOLUTE MAXIMUM RATINGS

 $T_A = 25^{\circ}C$, unless otherwise noted.

Table 3.

Parameter	Value
V _{DD} to GND	–0.3 V to +7 V
V _A , V _B , V _W to GND	$GND - 0.3 V$, $V_{DD} + 0.3 V$
I _{MAX}	
Pulsed ¹	±20 mA
Continuous	±5 mA
Digital Inputs and Output Voltage to GND	0 V to +7 V
Operating Temperature Range	-40°C to +85°C
Maximum Junction Temperature (T _{JMAX})	150°C
Storage Temperature	–65°C to +150°C
Lead Temperature (Soldering, 10 sec)	300°C
Thermal Resistance ² θ _{JA} : MSOP – 10	200°C/W

¹ Maximum terminal current is bounded by the maximum current handling of the switches, maximum power dissipation of the package, and maximum applied voltage across any two of the A, B, and W terminals at a given resistance.

² Package power dissipation = $(T_{JMAX} - T_A)/\theta_{JA}$.

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although this product features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

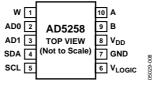
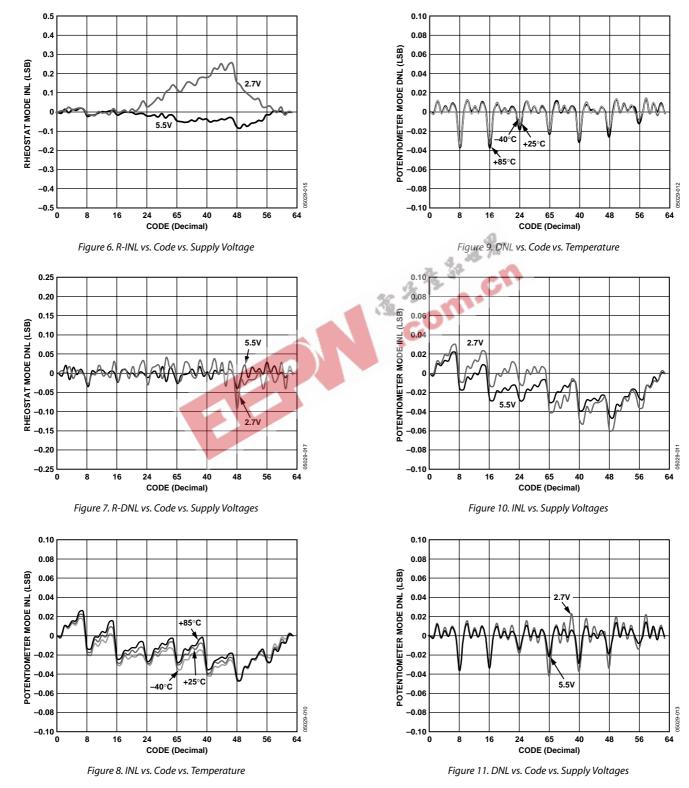


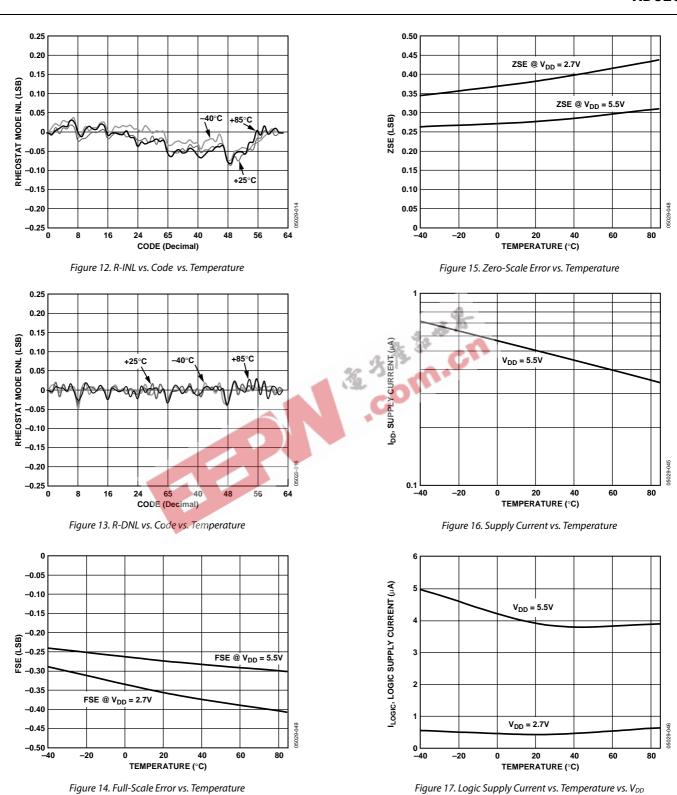
Figure 5. Pin Configuration

Pin No.	Mnemonic	Description
1	W	W Terminal, $GND \le V_W \le V_{DD}$.
2	ADO	Programmable Three-State Address Bit 0 for Multiple Package Decoding. State is registered on power-up.
3	AD1	Programmable Three-State Address Bit 1 for Multiple Package Decoding. State is registered on power-up.
4	SDA	Serial Data Input/Output.
5	SCL	Serial Clock Input. Positive edge triggered.
6	VLOGIC	Logic Power Supply.
7	GND	Serial Data Input/Output. Serial Clock Input. Positive edge triggered. Logic Power Supply. Digital Ground. Positive Power Supply.
8	V _{DD}	Positive Power Supply.
9	В	B Terminal, $GND \le V_B \le V_{DD}$.
10	А	A Terminal, $GND \le V_A \le V_{DD}$.

TYPICAL PERFORMANCE CHARACTERISTICS

 $V_{DD} = V_{LOGIC} = 5.5 \text{ V}, R_{AB} = 10 \text{ k}\Omega, T_A = 25^{\circ}\text{C}$, unless otherwise noted.





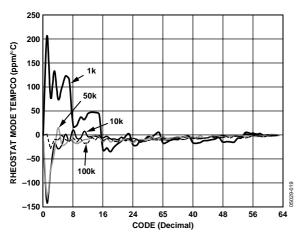


Figure 18. Rheostat Mode Tempco $(\Delta R_{AB} \times 10^6)/(R_{AB} \times \Delta T)$ vs. Code

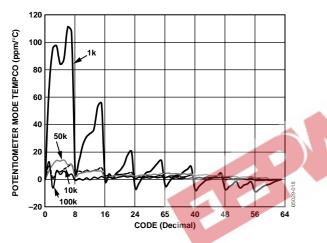


Figure 19. Potentiometer Mode Tempco ($\Delta V_W \times 10^6$)/($V_W \times \Delta T$) vs. Code

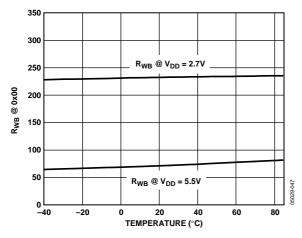


Figure 20. R_{WB} vs. Temperature

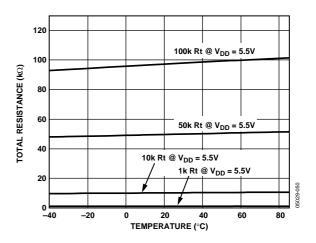


Figure 21. Total Resistance vs. Temperature

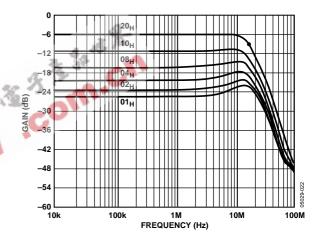


Figure 22. Gain vs. Frequency vs. Code, $R_{AB} = 1 \ k\Omega$

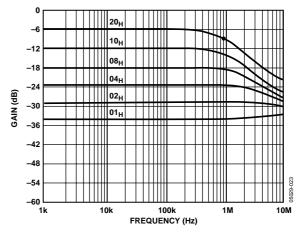
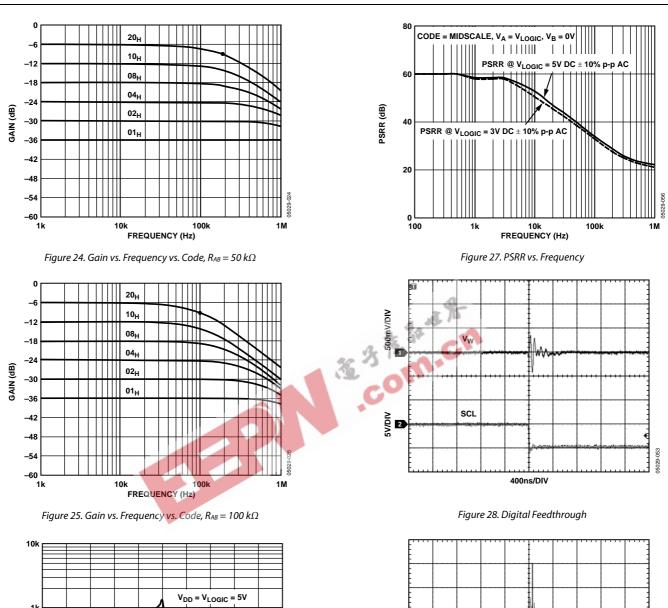


Figure 23. Gain vs. Frequency vs. Code, $R_{AB} = 10 k\Omega$



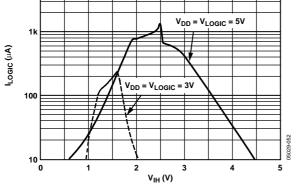


Figure 26. Logic Supply Current vs. Input Voltage

Figure 29. Midscale Glitch, Code 0×7F to 0×80

1μ**s/DIV**

05029-

vw

200mV/DIV

1

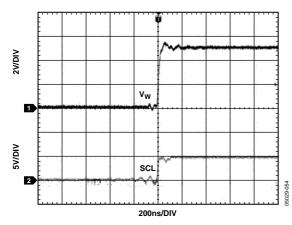


Figure 30. Large Signal Settling Time



TEST CIRCUITS

Figure 31 through Figure 36 illustrate the test circuits that define the test conditions used in the product specification tables.

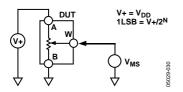


Figure 31. Test Circuit for Potentiometer Divider Nonlinearity Error (INL, DNL)

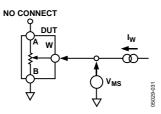


Figure 32. Test Circuit for Resistor Position Nonlinearity Error (Rheostat Operation; R-INL, R-DNL)

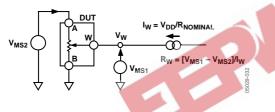


Figure 33. Test Circuit for Wiper Resistance

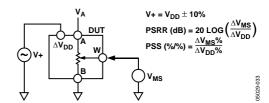
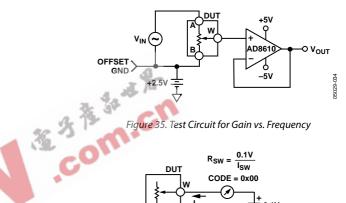


Figure 34. Test Circuit for Power Supply Sensitivity (PSS, PSSR)



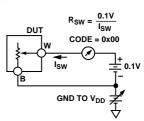


Figure 36. Test Circuit for Common-Mode Leakage Current

THEORY OF OPERATION

The AD5258 is a 64-position digitally controlled variable resistor (VR) device. The wiper's default value, prior to programming the EEPROM, is midscale.

PROGRAMMING THE VARIABLE RESISTOR

Rheostat Operation

The nominal resistance (R_{AB}) of the RDAC between Terminal A and Terminal B is available in 1 k Ω , 10 k Ω , 50 k Ω , and 100 k Ω . The nominal resistance of the VR has 64 contact points accessed by the wiper terminal. The 6-bit data in the RDAC latch is decoded to select one of 64 possible settings.

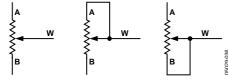


Figure 37. Rheostat Mode Configuration

The general equation determining the digitally programmed output resistance between Wiper W and Terminal B is

$$R_{WB}(D) = \frac{D}{64} \times R_{AB} + 2 \times R_{W}$$

where:

D is the decimal equivalent of the binary code loaded in the 6-bit RDAC register.

 R_{AB} is the end-to-end resistance.

 R_W is the wiper resistance contributed by the on resistance of each internal switch.

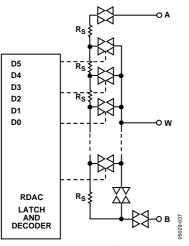


Figure 38. AD5258 Equivalent RDAC Circuit

Note that in the zero-scale condition, there is a relatively low value finite wiper resistance. Care should be taken to limit the current flow between Wiper W and Terminal B in this state to a maximum pulse current of no more than 20 mA. Otherwise, degradation or destruction of the internal switch contact can occur. Similar to the mechanical potentiometer, the resistance of the RDAC between Wiper W and Terminal A produces a digitally controlled complementary resistance, R_{WA} . The resistance value setting for R_{WA} starts at a maximum value of resistance and decreases as the data loaded in the latch increases in value. The general equation for this operation is

$$R_{WA}(D) = \frac{64 - D}{64} \times R_{AB} + 2 \times R_W \tag{2}$$

Typical device-to-device matching is process lot dependent and may vary by up to $\pm 30\%$. For this reason, resistance tolerance is stored in the EEPROM such that the user will know the actual R_{AB} within 0.1%.

PROGRAMMING THE POTENTIOMETER DIVIDER

Voltage Output Operation

The digital potentiometer easily generates a voltage divider at Wiper W-to-Terminal B and Wiper W-to-Terminal A proportional to the input voltage at Terminal A to Terminal B. Unlike the polarity of V_{DD} to GND, which must be positive, voltage across Terminal A to Terminal B, Wiper W to Terminal A, and Wiper W to Terminal B can be at either polarity.

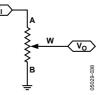


Figure 39. Potentiometer Mode Configuration

If ignoring the effect of the wiper resistance for approximation, connecting the A terminal to 5 V and the B terminal to ground produces an output voltage at Wiper W-to-Terminal B starting at 0 V up to 1 LSB less than 5 V. The general equation defining the output voltage at V_W with respect to ground for any valid input voltage applied to Terminal A and Terminal B is

$$V_W(D) = \frac{D}{64}V_A + \frac{64 - D}{64}V_B$$
(3)

A more accurate calculation, which includes the effect of wiper resistance, $V_{\rm W},$ is

$$V_{W}(D) = \frac{R_{WB}(D)}{R_{AB}} V_{A} + \frac{R_{WA}(D)}{R_{AB}} V_{B}$$
(4)

Operation of the digital potentiometer in the divider mode results in a more accurate operation over temperature. Unlike the rheostat mode, the output voltage is dependent mainly on the ratio of the Internal Resistors, R_{WA} and R_{WB}, and not the absolute values.

(1)

I²C INTERFACE

Note that the wiper's default value, prior to programming the EEPROM, is midscale.

1. The master initiates data transfer by establishing a START condition when a high-to-low transition on the SDA line occurs while SCL is high (see Figure 4). The next byte is the slave address byte, which consists of the slave address (first 7 bits) followed by an R/\overline{W} bit (see Table 6). When the R/\overline{W} bit is high, the master reads from the slave device. When the R/\overline{W} bit is low, the master writes to the slave device.

The slave address of the part is determined by two threestate-configurable Address Pins AD0 and AD1. The state of these two pins is registered upon power-up and decoded into a corresponding I²C 7-bit address (see Table 5). The slave address corresponding to the transmitted address bits responds by pulling the SDA line low during the ninth clock pulse (this is termed the slave acknowledge bit).

At this stage, all other devices on the bus remain idle while the selected device waits for data to be written to, or read from, its serial register.

2. Writing: In the write mode, the last bit (R/W) of the slave address byte is logic low. The second byte is the instruction byte. The first three bits of the instruction byte are the command bits (see Table 6). The user must choose whether to write to the RDAC register, EEPROM register, or activate the software write protect (see Table 7 to Table 10). The final five bits are all zeros (see Table 13 to Table 14). The slave again responds by pulling the SDA line low during the ninth clock pulse.

The final byte is the data byte MSB first. Don't cares can be left either high or low. In the case of the write protect mode, data is not stored; rather, a logic high in the LSB enables write protect. Likewise, a logic low will disable write protect. The slave again responds by pulling the SDA line low during the ninth clock pulse.

3. **Storing/Restoring:** In this mode, only the address and instruction bytes are necessary. The last bit (R/\overline{W}) of the address byte is logic low. The first three bits of the instruction byte are the command bits (see Table 6). The two choices are transfer data from RDAC to EEPROM

(store), or from EEPROM to RDAC (restore). The final five bits are all zeros (see Table 13 to Table 14).

4. **Reading:** Assuming the register of interest was not just written to, it is necessary to write a dummy address and instruction byte. The instruction byte will vary depending on whether the data that is wanted is the RDAC register, EEPROM register, or tolerance register (see Table 11 to Table 16).

After the dummy address and instruction bytes are sent, a repeat start is necessary. After the repeat start, another address byte is needed, except this time the R/\overline{W} bit is logic high. Following this address byte is the readback byte containing the information requested in the instruction byte. Read bits appear on the negative edges of the clock. Don't cares may either be in a high or low state.

The tolerance register can be read back individually (see Table 15) or consecutively (see Table 16). Refer to the Read Modes section for detailed information on the interpretation of the tolerance bytes.

After all data bits have been read or written, a STOP condition is established by the master. A STOP condition is defined as a low-to-high transition on the SDA line while SCL is high. In write mode, the master pulls the SDA line high during the tenth clock pulse to establish a STOP condition (see Figure 45). In read mode, the master issues a no acknowledge for the ninth clock pulse (that is, the SDA line remains high). The master then brings the SDA line low before the tenth clock pulse, and then raises SDA high to establish a STOP condition (see Figure 46).

A repeated write function gives the user flexibility to update the RDAC output a number of times after addressing and instructing the part only once. For example, after the RDAC has acknowledged its slave address and instruction bytes in the write mode, the RDAC output is updated on each successive byte until a STOP condition is received. If different instructions are needed, the write/read mode has to start again with a new slave address, instruction, and data byte. Similarly, a repeated read function of the RDAC is also allowed.

I²C BYTE FORMATS

The following generic, write, read, and store/restore control registers for the AD5258 all refer to the device addresses listed in Table 5, and the mode/condition reference key (S, P, SA, MA, NA, \overline{W} , R, and X) listed below.

S = Start Condition

 \mathbf{P} = Stop Condition

SA = Slave Acknowledge

MA = Master Acknowledge

NA = No Acknowledge

 $\overline{\mathbf{W}} = Write$

GENERIC INTERFACE

R =	= Read																	s.				
X =	= Don't Care														-ð:	20	Å	M	^			
	ENERIC INTERFACE	Eann											8	3	13	~		C				
1 a		гогш	ai	1				-	-	_	<u> </u>				-		r –		1			
	7-Bit Device Address																					
S	(See Table 5)	R/W	SA	C2	C 1	C0	A4 /	A3 A	2	A1	A0	SA	D7	D6	D5	D4	D3	D2	D1	D0	SA	Ρ
	Slave Address Byte				2	_		on By									Byte					

Table 7. RDAC-to-EEPROM Interface Command Descriptions

C2	C1	C0	Command Description
0	0	0	Operation between I ² C and RDAC
0	0	1	Operation between I ² C and EEPROM
0	1	0	Operation between I ² C and Write Protection Register. See Table 10.
1	0	0	NOP
1	0	1	Restore EEPROM to RDAC
1	1	0	Store RDAC to EEPROM

Table 5. Device Address Lookup

AD1 and AD0 are three-state address pins.

0011000 0 0 0011001 NC 0 0011010 1 0 0101001 0 NC 0101010 NC NC 0101011 1 NC 0101011 1 NC 0101011 1 NC 0101100 0 1	Device Address	AD1	AD0
0011010 1 0 0101001 0 NC 0101010 NC NC 0101011 1 NC	0011000	0	0
0101001 0 NC 0101010 NC NC 0101011 1 NC	0011001	NC	0
0101010 NC NC 0101011 1 NC	0011010	1	0
0101011 1 NC	0101001	0	NC
	0101010	NC	NC
1001100 0 1	0101011	1	NC
	1001100	0	1
1001101 NC 1	1001101	NC	1
1001110 1 1	1001110	1	1

WRITE MODES

Table 8. Writing to RDAC Register

1																						
	7-Bit Device Address																					
S	(See Table 5)	0	SA	0	0	0	0	0	0	0	0	SA	х	Х	D5	D4	D3	D2	D1	D0	SA	Р
	Classa Address Durts					Inc	tructi	ion By	rt o							Data	Byte					
	Slave Address Byte					INS	structi	юп ву	yte							Dala	Буте					
Table	slave Address Byte	ter				IIIS	structi		le							Dala	byte				<u> </u>	
Table	,	ter	<u> </u>			IIIS	structi		le							Data	byte				I 	

Instruction Byte

The wiper's default value, prior to programming the EEPROM, is midscale.

Table 10. Activating/Deactivating Software Write Protect

Slave Address Byte

	0 0																					
	7-Bit Device Address																					
S	(See Table 5)	0	SA	0	1	0	0	0	0	0	0	SA	0	0	0	0	0	0	0	WP	SA	Р
	Slave Address Byte					Ins	struct	ion By	yte							Data	Byte					

In order to activate the write protection mode, the WP bit in Table 10 must be logic high. In order to deactivate the write protection, the command must be sent again except with the WP in logic zero state.

READ MODES

Read modes are referred to as traditional because the first two bytes for all three cases are "dummy" bytes which function to place the pointer towards the correct register. This is the reason for the repeat start. In theory, this step can be avoided if the user is interested in reading a register that was previously written to. For example, if the EEPROM was just written to, then the user can skip the two dummy bytes and proceed directly to the slave address byte followed by the EEPROM readback data.

Data Byte

Table 11. Traditional Readback of RDAC Register Value

	7-Bit Device Address													7-Bit Device Address											
S	(See Table 5)	0	SA	0	0	0	0	0	0	0	0	SA	S	(See Table 5)	1	SA	х	х	D5	D4	D3	D2	D1 [D0 N/	ΑP
	Slave Address Byte					Insti	ruct	ion	Byte	5				Slave Address Byte				F	Read	d Ba	ck D)ata			
												-		•											

Repeat start

Table 12. Traditional Readback of Stored EEPROM Value

10	ible 12. Haditional Re	auu	Jack	U	5101	.cu	LLI	ĸo	101	v ali	uc														
	7-Bit Device Address													7-Bit Device Address											
S	(See Table 5)	0	SA	0	0	1	0	0	0	0	0	SA	S	(See Table 5)	1	SA	х	х	D5	D4	D3	D2	D1	D0 N	JA P
	Slave Address Byte					Insti	ruct	ion	Byte	ē				Slave Address Byte				l	Rea	d Ba	nck D	Data	1		
													▲												

| Repeat start

STORE/RESTORE MODES

Table 13. Storing RDAC Value to EEPROM

	7-Bit Device Address												
S	(See Table 5)	0	SA	1	1	0	0	0	0	0	0	SΑ	Ρ
	Slave Address Byte			1	ns	tru	ict	ior	۱B	vte	2		

Т	able 14. Restoring I	EE	PR	DI	M	to	R	D	A	С			
	7-Bit Device Address												
S	(See Table 5)	0	SΑ	1	0	1	0	0	0	0	0	SA	Ρ
	Slave Address Byte			I	ns	trι	ict	ior	n B	yte	Ĵ		

TOLERANCE READBACK MODES

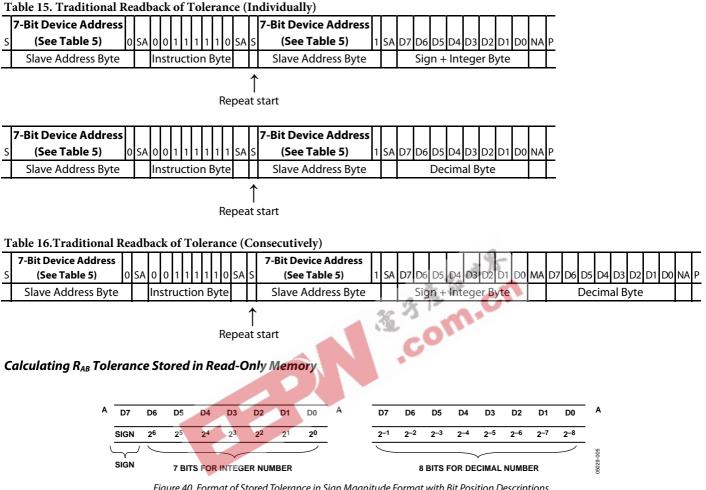


Figure 40. Format of Stored Tolerance in Sign Magnitude Format with Bit Position Descriptions. (Unit is Percent. Only Data Bytes are Shown.)

The AD5258 features a patented R_{AB} tolerance storage in the nonvolatile memory. The tolerance is stored in the memory during factory production and can be read by users at any time. The knowledge of stored tolerance allows users to accurately calculate R_{AB} . This feature is valuable for precision, rheostat mode, and open-loop applications where knowledge of absolute resistance is critical.

The stored tolerance resides in the read-only memory and is expressed as a percentage. The tolerance is stored in two memory location bytes in sign magnitude binary form (see Figure 40). The two EEPROM address bytes are 11110 (sign + integer) and 11111 (decimal number). The two bytes can be individually accessed with two separate commands (see Table 15). Alternatively, readback of the first byte followed by the second byte can be done in one command (see Table 16). In the latter case, the memory pointer will automatically increment from the first to the second EEPROM location (increments from 11110 to 11111) if read consecutively.

In the first memory location, the MSB is designated for the sign (0 = + and 1 = -) and the seven LSBs are designated for the integer portion of the tolerance. In the second memory location, all eight data bits are designated for the decimal portion of tolerance. Note that the decimal portion has a limited accuracy of only 0.1%. For example, if the rated $R_{AB} = 10 \text{ k}\Omega$ and the data readback from Address 11110 shows 0001 1100, and Address 11111 shows 0000 1111, then the tolerance can be calculated as

$$\begin{split} MSB: 0 &= + \\ Next \ 7 \ MSB: \ 001 \ 1100 &= 28 \\ 8 \ LSB: \ 0000 \ 1111 &= 15 \times 2^{-8} &= 0.06 \\ Tolerance &= +28.06\% \\ Rounded \ Tolerance &= +28.1\% \ and \ therefore, \\ R_{AB_ACTUAL} &= 12.810 \ k\Omega \end{split}$$

ESD PROTECTION OF DIGITAL PINS AND RESISTOR TERMINALS

The AD5258 V_{DD}, V_{LOGIC}, and GND power supplies define the boundary conditions for proper 3-terminal and digital input operation. Supply signals present on Terminal A, Terminal B, and Terminal W that exceed V_{DD} or GND are clamped by the internal forward biased ESD protection diodes (see Figure 41). Digital Input SCL and Digital Input SDA are clamped by ESD protection diodes with respect to V_{LOGIC} and GND as shown in Figure 42.

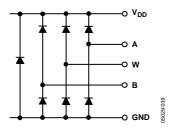


Figure 41. Maximum Terminal Voltages Set by VDD and GND

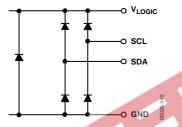


Figure 42. Maximum Terminal Voltages Set by VLOGIC and GND

POWER-UP SEQUENCE

Because the ESD protection diodes limit the voltage compliance at Terminal A, Terminal B, and Terminal W (see Figure 41), it is important to power GND/V_{DD}/V_{LOGIC} before applying any voltage to Terminal A, Terminal B, and Terminal W; otherwise, the diode is forward biased such that V_{DD} and V_{LOGIC} are powered unintentionally and may affect the user's circuit. The ideal power-up sequence is in the following order: GND, V_{DD}, V_{LOGIC}, digital inputs, and then V_A, V_B, V_W. The relative order of powering V_A, V_B, V_W, and the digital inputs is not important as long as they are powered after GND/V_{DD}/V_{LOGIC}.

LAYOUT AND POWER SUPPLY BYPASSING

It is good practice to employ compact, minimum lead length layout design. The leads to the inputs should be as direct as possible with minimum conductor length. Ground paths should have low resistance and low inductance. Similarly, it is also good practice to bypass the power supplies with quality capacitors for optimum stability. Supply leads to the device should be bypassed with disc or chip ceramic capacitors of 0.01 μ F to 0.1 μ F. Low ESR 1 μ F to 10 μ F tantalum or electrolytic capacitors should also be applied at the supplies to minimize any transient disturbance and low frequency ripple (see Figure 43). The digital ground should also be joined remotely to the analog ground at one point to minimize the ground bounce.

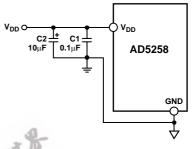


Figure 43. Power Supply Bypassing

MULTIPLE DEVICES ON ONE BUS

The AD5258 has two three-state configurable Address Pins AD0 and AD1. The state of these two pins is registered upon power-up and decoded into a corresponding I²C 7-bit address (see Table 5). This allows up to nine devices on the bus to be written to, or read from, independently. In the case that the pin is assigned to be floated, the static voltage will be $V_{LOGIC}/2$.

EVALUATION BOARD

An evaluation board, along with all necessary software, is available to program the AD5258 from any PC running Windows* 98/2000/XP. The graphical user interface, as shown in Figure 44, is straightforward and easy to use. More detailed information is available in the user manual that comes with the board.

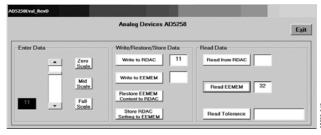
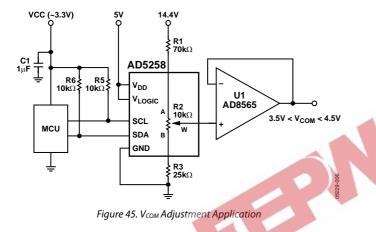


Figure 44. AD5258 Evaluation Board Software

DISPLAY APPLICATIONS circuitry

A special feature of the AD5258 is its unique separation of the V_{LOGIC} and V_{DD} supply pins. The reason for doing this is to provide greater flexibility in applications that do not always provide needed supply voltages.

In particular, LCD panels often require a V_{COM} voltage in the range of 3 V to 5 V. The circuit in Figure 45 is the rare exception in which a 5 V supply is available to power the digital potentiometer.



In the more common case shown in Figure 46, only analog 14.4 V and digital logic 3.3 V supplies are available. By placing discrete resistors above and below the digital pot, V_{DD} can now be tapped off the resistor string itself. Based on the chosen resistor values, the voltage at V_{DD} in this case equals 4.8 V, allowing the wiper to be safely operated all the way up to 4.8 V. The current draw of

 $V_{\rm DD}$ will not affect that node's bias because it is only on the order of microamps. $V_{\rm LOGIC}$ is tied to the MCU's 3.3 V digital supply because $V_{\rm LOGIC}$ will draw the 35 mA which is needed when writing to the EEPROM. It would be impractical to try and source 35 mA through the 70 k Ω resistor, therefore, $V_{\rm LOGIC}$ is not connected to the same node as $V_{\rm DD}$.

For this reason, V_{LOGIC} and V_{DD} are provided as two separate supply pins that can either be tied together or treated independently; V_{LOGIC} supplying the logic/EEPROM with power, and V_{DD} biasing up the A, B, and W terminals for added flexibility.

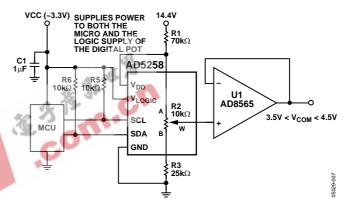
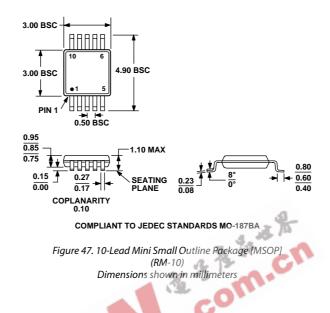


Figure 46. Circuitry When a Separate Supply is Not Available for V_{DD}

For a more detailed look at this application, refer to the article, "Simple VCOM Adjustment uses any Logic Supply Voltage" in the September 30, 2004, issue of *EDN* magazine.

OUTLINE DIMENSIONS



ORDERING GUIDE

Model	R _{AB} (Ω)	Temperature	Package Description	Package Option	Branding
AD5258BRMZ11	1 k	–40°C to +85°C	MSOP-10	RM-10	D4K
AD5258BRMZ1-R71	1 k	-40°C to +85°C	MSOP-10	RM-10	D4K
AD5258BRMZ101	10 k	-40°C to +85°C	MSOP-10	RM-10	D4L
AD5258BRMZ10-R71	10 k	-40°C to +85°C	MSOP-10	RM-10	D4L
AD5258BRMZ501	50 k	–40°C to +85°C	MSOP-10	RM-10	D4M
AD5258BRMZ50-R71	50 k	-40°C to +85°C	MSOP-10	RM-10	D4M
AD5258BRMZ1001	100 k	–40°C to +85°C	MSOP-10	RM-10	D4N
AD5258BRMZ100-R71	100 k	–40°C to +85°C	MSOP-10	RM-10	D4N
AD5258EVAL ²			Evaluation Board		

 1 Z = Pb-free part.

 2 The evaluation board is shipped with the 10 k Ω R_{AB} resistor option; however, the board is compatible with all available resistor value options.

NOTES



NOTES



NOTES



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